Lecture 10

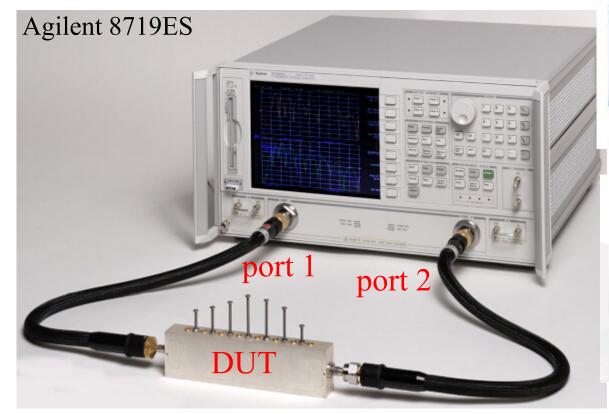
Vector Network Analyzers and Signal Flow Graphs

Sections: 6.7 and 6.11

Homework: From Section 6.13 Exercises: 4, 5, 6, 7, 9, 10, 22

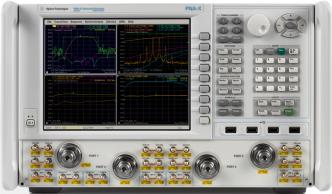
Acknowledgement: Some diagrams and photos are from M. Steer's book "Microwave and RF Design"

Vector Network Analyzers





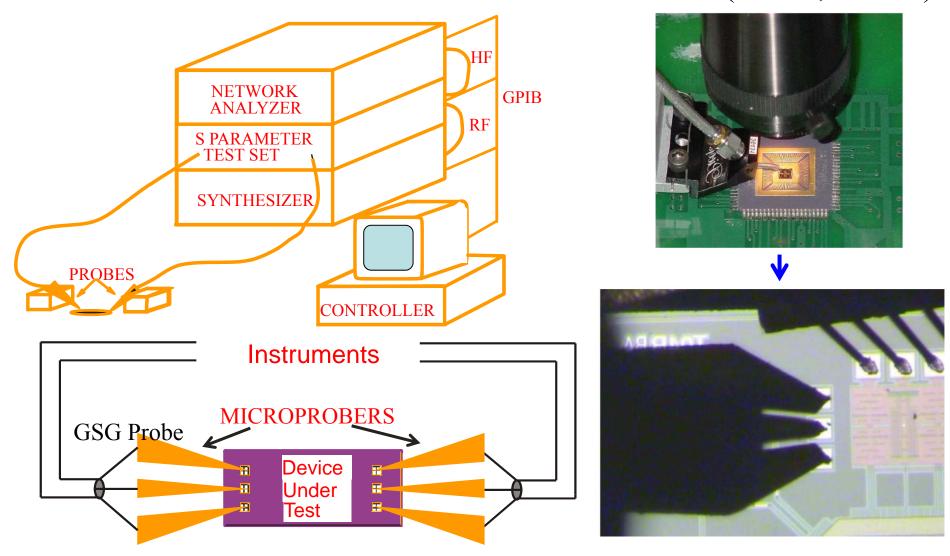
R&S®ZVA67 VNA 2 ports, 67 GHz



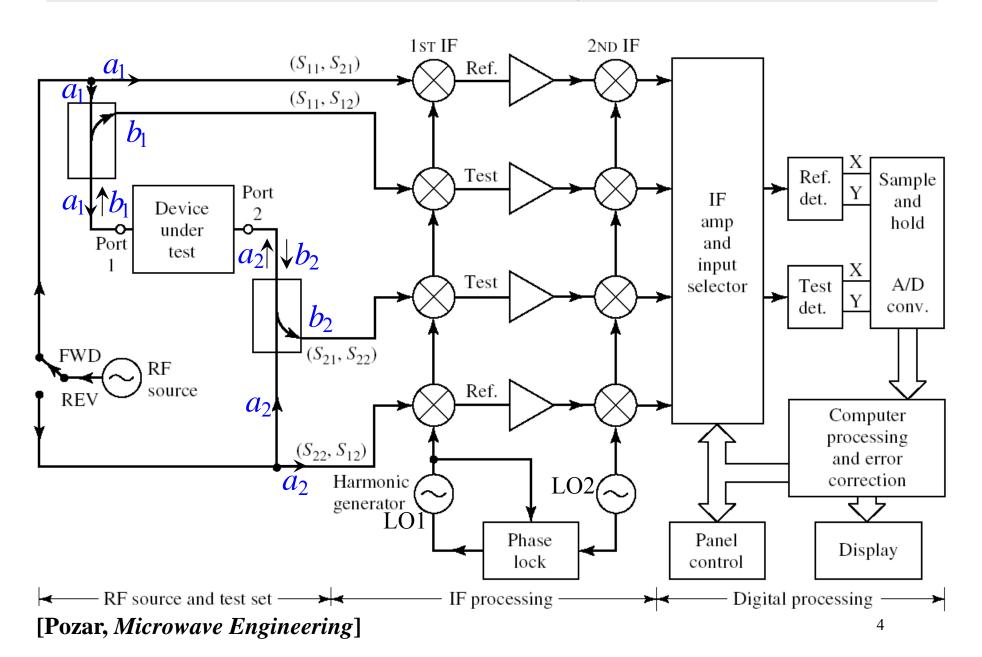
Agilent N5247A PNA-X VNA, 4 ports, 67 GHz

Vector Network Analyzer and IC Probes

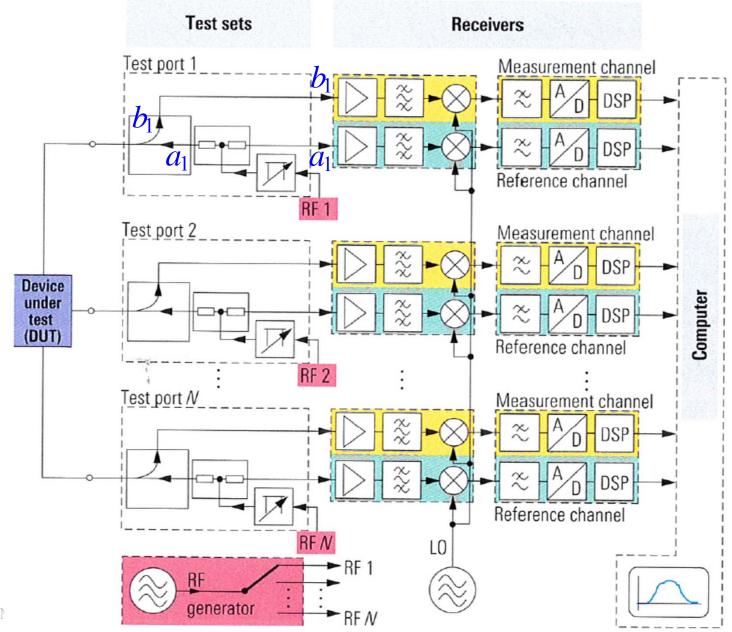
measurements of circuits with non-coaxial connectors (HMIC, MMIC)



2-Port Vector Network Analyzer: Schematic



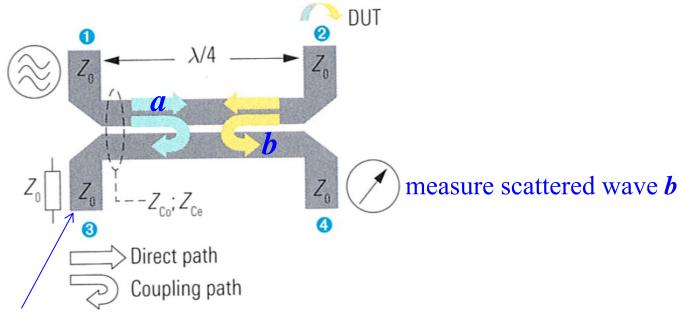
N-Port Vector Network Analyzer: Schematic



[Hiebel, Fundamentals of Vector Network Analysis]

Vector Network Analyzer: Directional Element

reversed directional coupler



port 3 terminated with a matched load (power is absorbed, not used)

Signal Flow Graphs

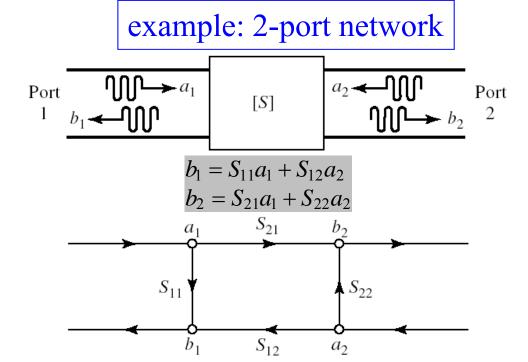
- > used to analyze microwave circuits in terms of incident and scattered waves
- > used to devise calibration techniques for VNA measurements
- > components of a signal flow graph

nodes

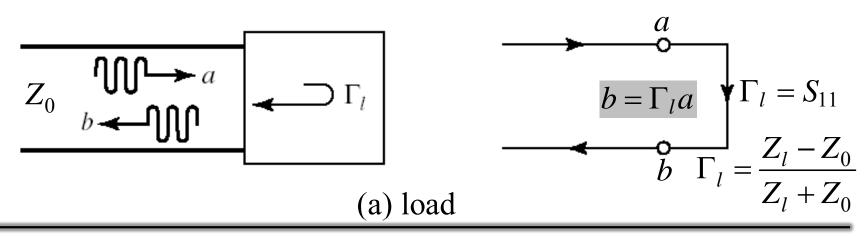
each port has two nodes, a_k and b_k

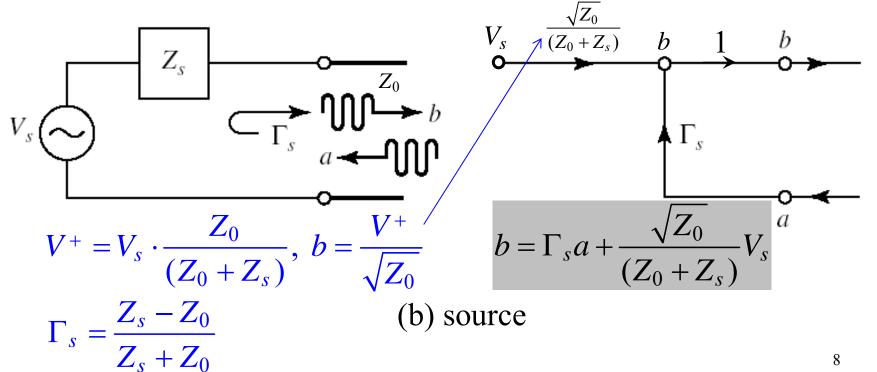
branches

- a branch shows the dependency between pairs of nodes
- it has a direction from input to output

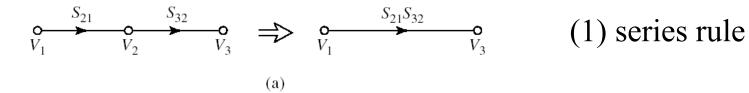


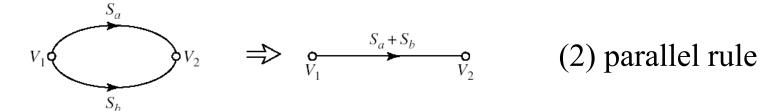
Signal Flow Graphs of Two Basic 1-port Networks





Decomposition Rules of Signal Flow Graphs





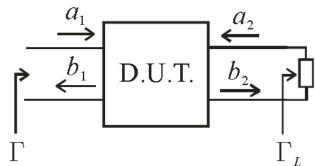
(b)

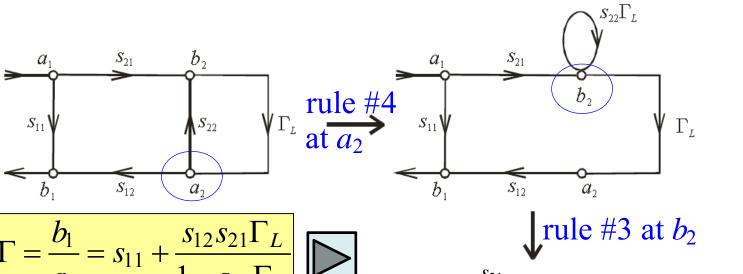
(d)

$$S_{21} \qquad S_{32} \qquad S_{32} \qquad S_{32} \qquad S_{32} \qquad S_{32} \qquad S_{33} \qquad S_{32} \qquad S_{33} \qquad S_{34} \qquad S$$

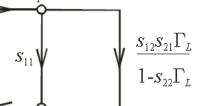
Signal Flow Graphs: Example

Express the input reflection coefficient Γ of a 2-port network in terms of the reflection at the load Γ_L and its *S*-parameters.

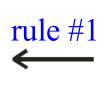


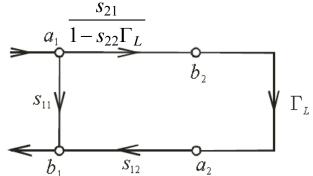


$$\Gamma = \frac{a_1}{a_1} = s_{11} + \frac{s_{12}s_{21}\Gamma_L}{1 - s_{22}\Gamma_L}$$



 b_1



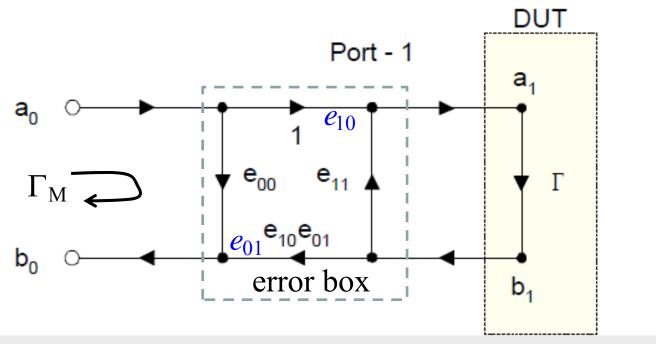


VNA Calibration for 1-port Measurements (3-term Error Model)

- the 3-term error model is known as the OSM (Open-Short-Matched) cal technique (aka OSL or SOL, Open-Short-Load)
- the *cal* procedure includes 3 measurements performed before the DUT is measured: 1) open circuit, 2) short circuit, 3) matched load
- used when $\Gamma = S_{11}$ of a single-port device is measured
- actual measurements include losses and phase delays in connectors and cables, leakage and parasitics inside the instrument these are viewed as a 2-port *error box*
- calibration aims at de-embedding these errors from the total measured *S*-parameters

3-term Error Model: Signal-flow Graph

[Rytting, Network Analyzer Error Models and Calibration Methods]



$$e_{00}$$
 = Directivity

$$e_{11}$$
 = Port Match

$$(e_{10}e_{01}) = Tracking$$

Note: SFG branches without a coefficient have a default coefficient of 1.

S-parameters of the error box contain 3 unknowns

$$S_E = \begin{bmatrix} e_{00} & 1 \\ e_{10}e_{01} & e_{11} \end{bmatrix} \iff S_E = \begin{bmatrix} e_{00} & e_{01} \\ e_{10} & e_{11} \end{bmatrix}$$

3-term Error Model: Error-term Equations

Measured

$$\Gamma_{\rm M} = \frac{b_0}{a_0} = \frac{e_{00} - \Delta_{\rm e} \Gamma}{1 - e_{11} \Gamma}$$

$$\Delta_{e} = e_{00}e_{11} - (e_{10}e_{01})$$

<u>Actual</u>



$$\Gamma = \frac{\Gamma_{\text{M}} C_{00}}{\Gamma_{\text{M}} e_{11} - \Delta_{\text{e}}}$$

$$\frac{error\ de-}{embedding}$$

$$\frac{formula}{(\text{see sl. 10})}$$

Using the result from the example on sl. 10 and the signal flow graph in sl. 12, prove the formula

$$\Gamma_{\rm M} = \frac{e_{00} - \Delta_e \cdot \Gamma}{1 - e_{11} \Gamma}$$



3-term Error Model

• the 3 calibration measurements with the 3 standard known loads (Γ_1 , Γ_2 , Γ_3) produce 3 equations for the 3 unknown error terms

$$\begin{vmatrix} \mathbf{e}_{00} + \Gamma_{1}\Gamma_{\text{M1}}\mathbf{e}_{11} - \Gamma_{1}\Delta_{\text{e}} = \Gamma_{\text{M1}} \\ \mathbf{e}_{00} + \Gamma_{2}\Gamma_{\text{M2}}\mathbf{e}_{11} - \Gamma_{2}\Delta_{\text{e}} = \Gamma_{\text{M2}} \\ \mathbf{e}_{00} + \Gamma_{3}\Gamma_{\text{M3}}\mathbf{e}_{11} - \Gamma_{3}\Delta_{\text{e}} = \Gamma_{\text{M3}} \end{vmatrix}$$

$$\begin{vmatrix} \mathbf{e}_{00} + \Gamma_{1}\Gamma_{\mathrm{M1}}\mathbf{e}_{11} - \Gamma_{1}\Delta_{\mathrm{e}} = \Gamma_{\mathrm{M1}} \\ \mathbf{e}_{00} + \Gamma_{2}\Gamma_{\mathrm{M2}}\mathbf{e}_{11} - \Gamma_{2}\Delta_{\mathrm{e}} = \Gamma_{\mathrm{M2}} \end{vmatrix} linear system for \mathbf{x}^{T} = [e_{00}, e_{11}, \Delta_{e}]$$

$$\begin{vmatrix} \mathbf{e}_{00} + \Gamma_{2}\Gamma_{\mathrm{M2}}\mathbf{e}_{11} - \Gamma_{2}\Delta_{\mathrm{e}} = \Gamma_{\mathrm{M2}} \\ \mathbf{e}_{00} + \Gamma_{3}\Gamma_{\mathrm{M3}}\mathbf{e}_{11} - \Gamma_{3}\Delta_{\mathrm{e}} = \Gamma_{\mathrm{M3}} \end{vmatrix}$$

$$\begin{vmatrix} \mathbf{e}_{00} + \Gamma_{3}\Gamma_{\mathrm{M3}}\mathbf{e}_{11} - \Gamma_{3}\Delta_{\mathrm{e}} = \Gamma_{\mathrm{M3}} \\ \mathbf{e}_{00} + \Gamma_{3}\Gamma_{\mathrm{M3}}\mathbf{e}_{11} - \Gamma_{3}\Delta_{\mathrm{e}} = \Gamma_{\mathrm{M3}} \end{vmatrix}$$

• ideally, in the OSM calibration,

$$\Gamma_1 = \Gamma_0 = 1$$

$$\Gamma_2 = \Gamma_s = -1$$

$$\Gamma_3 = \Gamma_m = 0$$

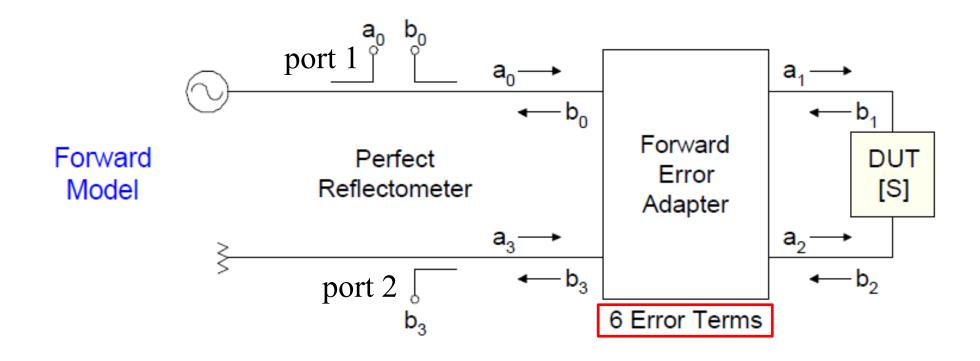
• for accurate results, one has to know the exact values of $\Gamma_{\rm o}$, $\Gamma_{\rm s}$ and $\Gamma_{\rm m}$ – use manufacturer's cal kits!

2-port Calibration: Classical 12-term Error Model

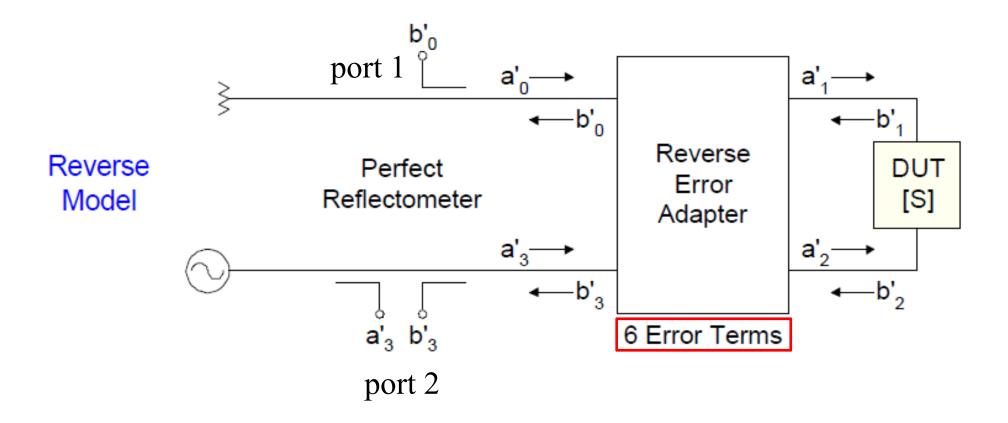
[Rytting, Network Analyzer Error Models and Calibration Methods]

consists of two models:

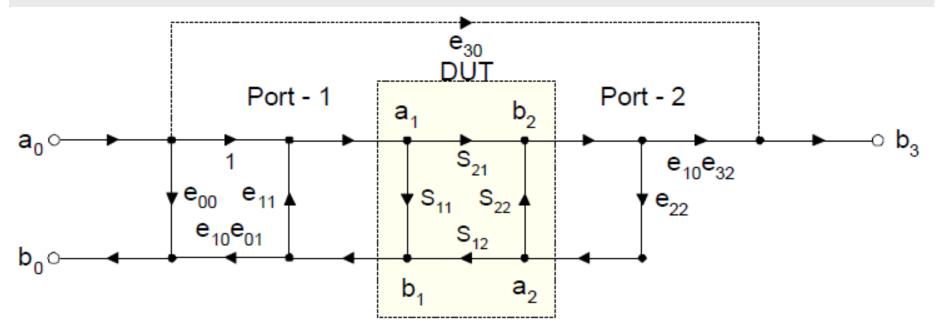
- forward (excitation at port 1): models errors in S_{11M} and S_{21M}
- \bullet reverse (excitation at port 2): models errors in $S_{22\mathrm{M}}$ and $S_{12\mathrm{M}}$



12-term Error Model: Reverse Model



12-term Error Model: Forward-model SFG



$$e_{00}$$
 = Directivity

$$(e_{10}e_{01})$$
 = Reflection Tracking

$$(e_{10}e_{32})$$
 = Transmission Tracking

$$e_{22}$$
 = Port-2 Match

$$e_{30}$$
 = Leakage

$$S_{11M} = \frac{b_0}{a_0} = e_{00} + (e_{10}e_{01}) \frac{S_{11} - e_{22}\Delta_S}{1 - e_{11}S_{11} - e_{22}S_{22} + e_{11}e_{22}\Delta_S}$$

$$S_{21M} = \frac{b_3}{a_0} = e_{30} + (e_{10}e_{32}) \frac{S_{21}}{1 - e_{11}S_{11} - e_{22}S_{22} + e_{11}e_{22}\Delta_S}$$

$$(*) \qquad \Delta_S = S_{11}S_{22} - S_{21}S_{12}$$

12-term Error Model: Forward-model SFG

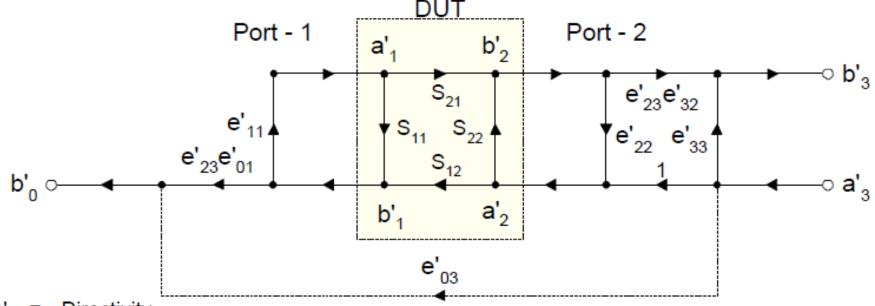
Using signal-flow graph transformations derive the formulas for S_{11M} and S_{21M} in the previous slide.

$$S_{11M} = \frac{b_0}{a_0} = e_{00} + (e_{10}e_{01}) \frac{S_{11} - e_{22}\Delta_S}{1 - e_{11}S_{11} - e_{22}S_{22} + e_{11}e_{22}\Delta_S}$$

$$S_{21M} = \frac{b_3}{a_0} = e_{30} + (e_{10}e_{32}) \frac{S_{21}}{1 - e_{11}S_{11} - e_{22}S_{22} + e_{11}e_{22}\Delta_S}$$

$$(*) \qquad \Delta_S = S_{11}S_{22} - S_{21}S_{12}$$

12-term Error Model: Reverse-model SFG



e'₃₃ = Directivity

$$S_{22M} = \frac{b'_{3}}{a'_{3}} = e'_{33} + (e'_{23}e'_{32}) \frac{S_{22} - e'_{11} \Delta_{S}}{1 - e'_{11}S_{11} - e'_{22}S_{22} + e'_{11}e'_{22} \Delta_{S}}$$

$$S_{12M} = \frac{b'_{0}}{a'_{3}} = e'_{03} + (e'_{23}e'_{01}) \frac{S_{12}}{1 - e'_{11}S_{11} - e'_{22}S_{22} + e'_{11}e'_{22} \Delta_{S}}$$

$$(**) \qquad \Delta_{S} = S_{11}S_{22} - S_{21}S_{12}$$

12-term Calibration Method

Step 1: Port 1 Calibration using the OSM 1-port procedure. Obtain e_{11} , e_{00} , and Δ_e , from which $(e_{10}e_{01})$ is obtained.



Step 2: Connect matched loads (Z_0) to both ports (*isolation*). $(S_{21} = 0)$ The measured S_{21M} yields e_{30} directly.

Step 3: Connect ports 1 and 2 directly (*thru*). $(S_{21} = S_{12} = 1, S_{11} = S_{22} = 0)$

Obtain
$$e_{22}$$
 and e_{10} e_{32} from eqns. (*) using
$$S_{21} = S_{12} = 1, S_{11} = S_{22} = 0.$$

$$\Rightarrow \begin{cases} e_{22} = \frac{S_{11M} - e_{00}}{S_{11M} e_{11} - \Delta_e} \\ e_{10} e_{32} = (S_{21M} - e_{30})(1 - e_{11} e_{22}) \end{cases}$$

- All 6 error terms of the forward model are now known.
- Same procedure is repeated for port 2.

12-term Calibration Method: Error De-embedding

$$\begin{split} S_{11} &= \frac{\left(\frac{S_{11M} - e_{00}}{e_{10}e_{01}}\right) \left[1 + \left(\frac{S_{22M} - e'_{33}}{e'_{23}e'_{32}}\right) e'_{22}\right] - e_{22} \left(\frac{S_{21M} - e_{30}}{e_{10}e_{32}}\right) \left(\frac{S_{12M} - e'_{03}}{e'_{23}e'_{01}}\right)}{D} \\ S_{21} &= \frac{\left(\frac{S_{21M} - e_{30}}{e_{10}e_{32}}\right) \left[1 + \left(\frac{S_{22M} - e'_{33}}{e'_{23}e'_{32}}\right) (e'_{22} - e_{22})\right]}{D} \\ S_{22} &= \frac{\left(\frac{S_{22M} - e'_{33}}{e'_{23}e'_{32}}\right) \left[1 + \left(\frac{S_{11M} - e_{00}}{e_{10}e_{01}}\right) e_{11}\right] - e'_{11} \left(\frac{S_{21M} - e_{30}}{e_{10}e_{32}}\right) \left(\frac{S_{12M} - e'_{03}}{e'_{23}e'_{01}}\right)}{D} \\ S_{12} &= \frac{\left(\frac{S_{12M} - e'_{03}}{e'_{23}e'_{01}}\right) \left[1 + \left(\frac{S_{11M} - e_{00}}{e_{10}e_{01}}\right) (e_{11} - e'_{11})\right]}{D} \end{split}$$

$$D = \left[1 + \left(\frac{S_{11M} - e_{00}}{e_{10}e_{01}}\right)e_{11}\right] \left[1 + \left(\frac{S_{22M} - e'_{33}}{e'_{23}}\right)e'_{22}\right] - \left(\frac{S_{21M} - e_{30}}{e_{10}e_{32}}\right)\left(\frac{S_{12M} - e'_{03}}{e'_{23}e'_{01}}\right)e_{22}e'_{11}$$

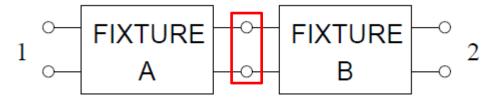
2-port Thru-Reflect-Line Calibration

- TRL (Thru-Reflect-Line) calibration is used when classical standards such as open, short and matched load cannot be realized
- TRL is the calibration used when measuring devices with non-coaxial terminations (HMIC and MMIC)
- TRL calibration is based on an 8-term error model
- TRL calibration requires three (2-port) calibration structures

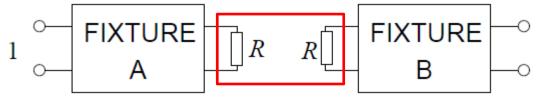
thru: the 2 ports must be connected directly, **sets the reference planes** *reflect*: load on each port identical; must have large reflection *line* (or *delay*): 2 ports connected with a matched (Z_0) transmission line (TL must represent the IC interconnect for the measured DUT)

Thru, Reflect, and Line Calibration Connections

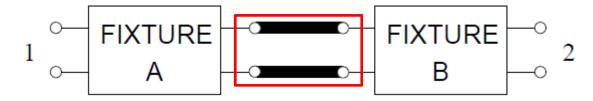
(a) thru



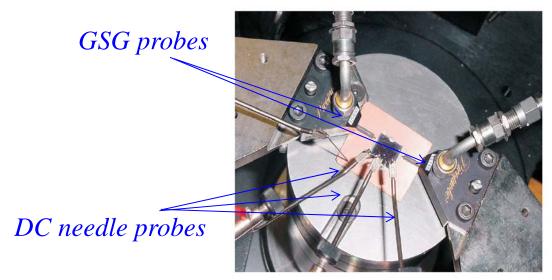
(b) reflect

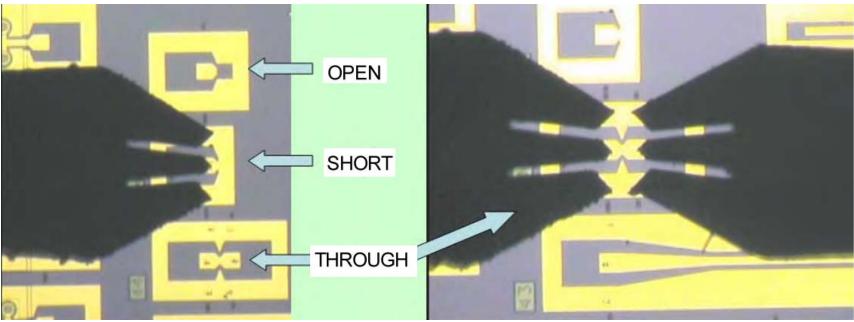


(c) line



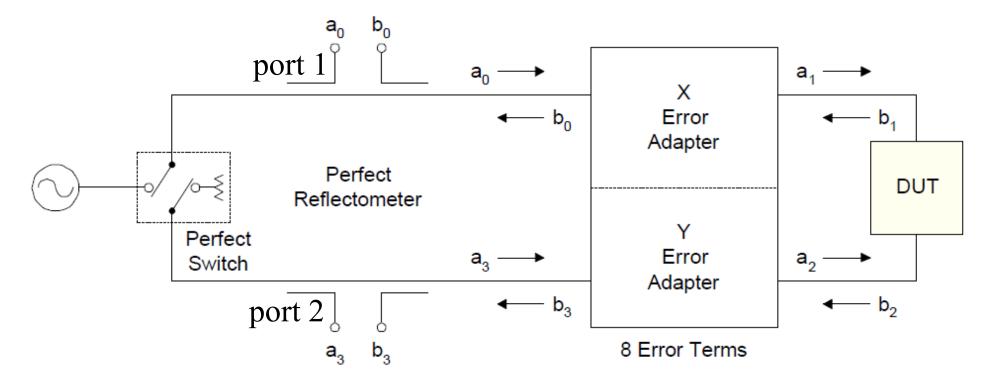
Thru-Reflect-Line Calibration Fixtures



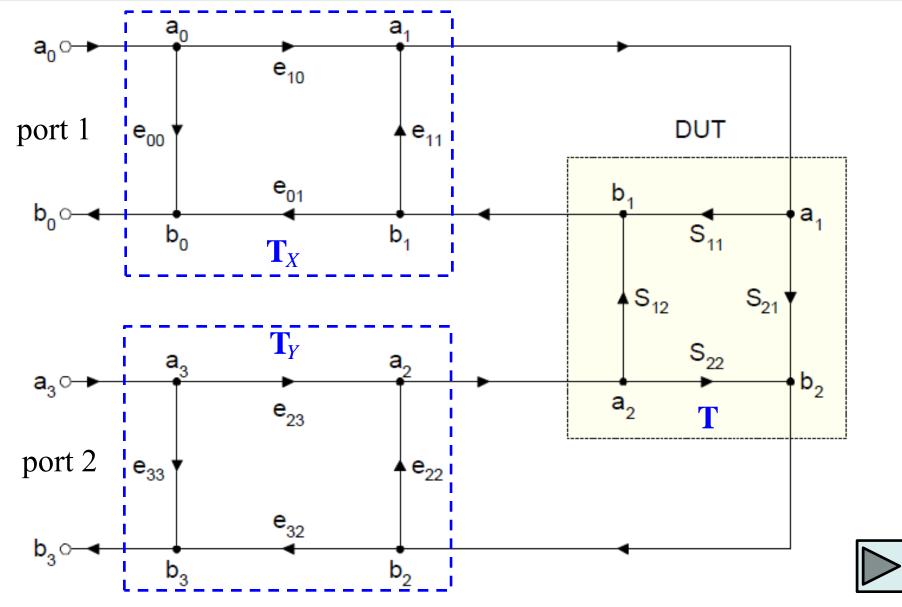


2-port Calibration: 8-term Error Model

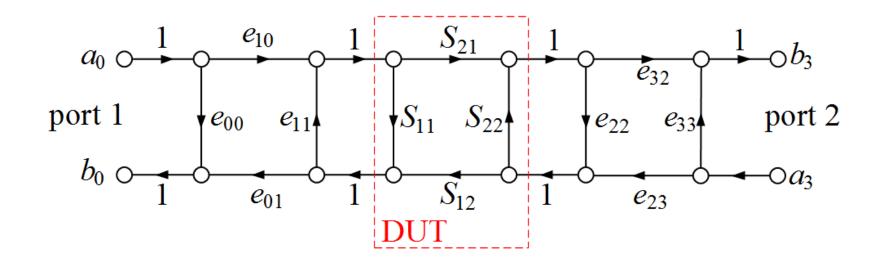
[Rytting, Network Analyzer Error Models and Calibration Methods]

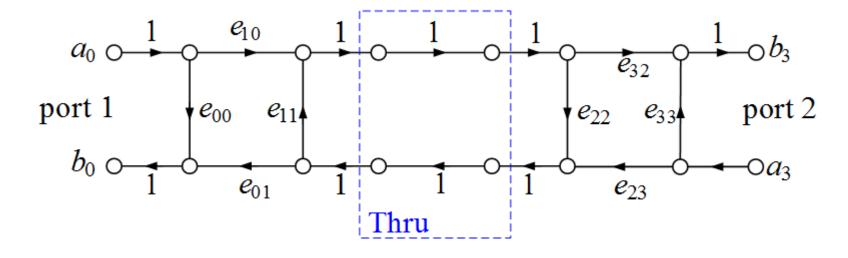


Signal-flow Graph of 8-term Error Model

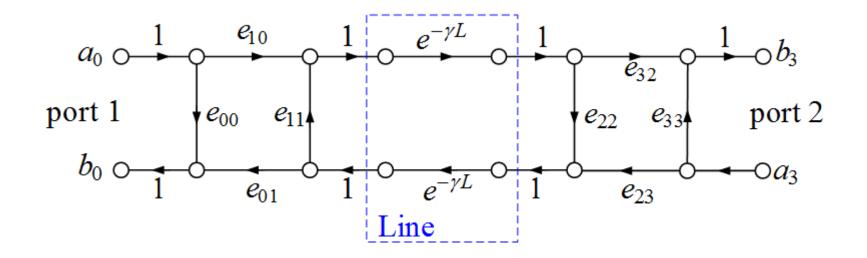


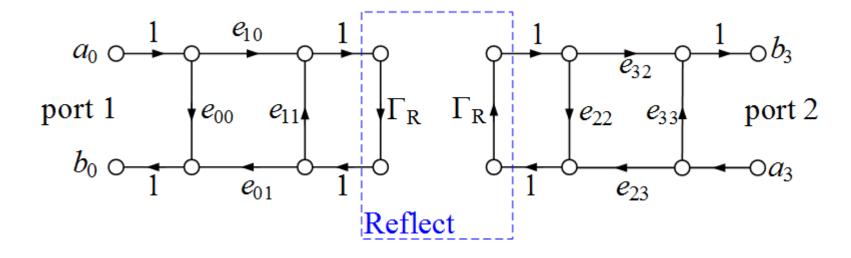
Signal-flow Graphs of the 3 TRL Calibration Measurements





Signal-flow Graphs of the 3 TRL Calibration Measurements (2)





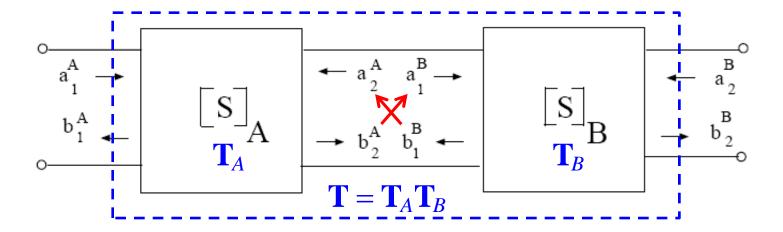
Scattering Transfer (or Cascade) Parameters

• when a network is a cascade of 2-port networks, often the scattering transfer (*T*-parameters) are used

$$\begin{bmatrix} V_1^- \\ V_1^+ \end{bmatrix} = \begin{bmatrix} T_{11} & T_{12} \\ T_{21} & T_{22} \end{bmatrix} \begin{bmatrix} V_2^+ \\ V_2^- \end{bmatrix} \quad \text{or} \quad \begin{bmatrix} b_1 \\ a_1 \end{bmatrix} = \begin{bmatrix} T_{11} & T_{12} \\ T_{21} & T_{22} \end{bmatrix} \begin{bmatrix} a_2 \\ b_2 \end{bmatrix}$$

• relation to S-parameters

$$\begin{bmatrix} T_{11} & T_{12} \\ T_{21} & T_{22} \end{bmatrix} = S_{21}^{-1} \begin{bmatrix} -\Delta_S & S_{11} \\ -S_{22} & 1 \end{bmatrix}, \ \Delta_S = S_{11}S_{22} - S_{12}S_{21}$$



8-term Error Model in Terms of *T*-parameters for TRL Calibration

<u>MEASURED</u>

<u>ACTUAL</u>

$$T_M = T_X T T_Y$$



$$T = T_X^{-1} T_M T_Y^{-1}$$

error de-embedding

$$\mathbf{T} = \frac{1}{S_{21}} \begin{bmatrix} -\Delta_S & S_{11} \\ -S_{22} & 1 \end{bmatrix}$$

$$\mathbf{T}_{\mathbf{M}} = \frac{1}{\mathbf{S}_{21\mathbf{M}}} \begin{bmatrix} -\Delta_{\mathbf{M}} & \mathbf{S}_{11\mathbf{M}} \\ -\mathbf{S}_{22\mathbf{M}} & 1 \end{bmatrix}$$

$$\Delta_{S} = S_{11}S_{22} - S_{12}S_{21}$$

$$\Delta_{M} = S_{11M}S_{22M} - S_{12M}S_{21M}$$

$$\mathbf{T}_{\mathbf{X}} = \frac{1}{\mathbf{e}_{10}} \begin{bmatrix} -\Delta_{\mathbf{X}} & \mathbf{e}_{00} \\ -\mathbf{e}_{11} & 1 \end{bmatrix}$$

$$\mathbf{T}_{\mathbf{Y}} = \frac{1}{\mathbf{e}_{32}} \begin{bmatrix} -\Delta_{\mathbf{Y}} & \mathbf{e}_{22} \\ -\mathbf{e}_{33} & 1 \end{bmatrix}$$

$$\Delta_{X} = e_{00}e_{11} - e_{10}e_{01}$$

$$\Delta_{Y} = e_{22}e_{33} - e_{32}e_{23}$$

8-term Error Model for TRL Calibration

• the number of unknown error terms is actually 7 in the simple cascaded TRL network (see sl. 26)

$$\mathbf{T}_{\mathbf{M}} = \underbrace{\frac{1}{(\mathbf{e}_{10}\mathbf{e}_{32})} \begin{bmatrix} -\Delta_{\mathbf{X}} & \mathbf{e}_{00} \\ -\mathbf{e}_{11} & 1 \end{bmatrix}}_{\mathbf{T}} \mathbf{T} \underbrace{\begin{bmatrix} -\Delta_{\mathbf{Y}} & \mathbf{e}_{22} \\ -\mathbf{e}_{33} & 1 \end{bmatrix}}_{\mathbf{T}} = \underbrace{\frac{1}{(\mathbf{e}_{10}\mathbf{e}_{32})}}_{\mathbf{A}} \mathbf{A} \mathbf{T} \mathbf{B}$$

$$\Rightarrow \mathbf{T} = (e_{10}e_{32})\mathbf{A}^{-1}\mathbf{T}_{\mathbf{M}}\mathbf{B}^{-1}$$

- TRL measurement procedure
 - (1) $\mathbf{T}_{\mathrm{M}} = \mathbf{T}_{\mathrm{X}} \mathbf{T} \mathbf{T}_{\mathrm{Y}} \rightarrow \text{measured with DUT}$
 - (2) $T_{M1} = T_X T_{C1} T_Y \rightarrow \text{measured with 2-port cal standard } #1$
 - (3) $T_{M2} = T_X T_{C2} T_Y \rightarrow$ measured with 2-port cal standard #2
 - (4) $T_{M3} = T_X T_{C3} T_Y \rightarrow$ measured with 2-port cal standard #3

8-term Error Model for TRL Calibration

- measuring the 3 two-port cal standards yields 12 independent equations while we have only 7 error terms
- thus 5 parameters of the 3 cal standards need not be known and can be determined from the calibration measurements
- which 5 parameters are chosen for which cal standards is important in order to reduce errors and avoid singular matrices
 - cal standard #1 T_{C1} must be completely known **thru**
 - cal standard #2 T_{C2} can have 2 unknown transmission terms line
 - cal standard #3 T_{C3} can have 3 unknowns; if its reflection coefficients satisfy $S_{11} = S_{22}$ (it is best if $S_{11} = S_{22}$ are large!) then its 3 coefficients can be unknown **reflect**

VNA Calibration – Summary

- errors are introduced when measuring a device due to parasitic coupling, leakage and imperfect connections
- these errors must be de-embedded from the overall measured *S*-parameters
- the de-embedding relies on the measurement of known or partially known cal standards calibration measurements, which precede the measurement of the DUT
- 1-port calibration uses the 3-term error model and the OSM method
- 2-port calibration may use 12-term or 8-term error models
- the 12-term error model requires OSM at each port, isolation, and thru measurements
- the 8-term error model with the TRL technique is widely used for non-coaxial devices
- there exists also a 16-term error model, many other cal techniques